

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	11	current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:56
L2	27	current AND voltage AND fault AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:57
L3	11	fault location AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
L4	14	(fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
L5	5	((("IC" OR integrated circuit) (semiconductor OR semi-conductor)) AND (fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404"))	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:34
L6	189433	(ishida.in. yamaguchi.in. hashimoto.in.)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:35
L7	36	(ishida.in. yamaguchi.in. hashimoto.in.) AND fault AND defect\$3 AND analysis AND ("IC" integrated circuit semi\$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:36

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L8	205	((("IC" OR integrated circuit) (semiconductor OR semi-conductor)) AND (fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404"))	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
L9	698	(fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
L10	278	current AND voltage AND fault AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
L11	77	current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:42
L12	8	signal\$1 AND fault AND current AND voltage AND (fault location defect\$3 signal\$1) AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
L13	8	signal\$1 AND fault\$1 AND current AND voltage AND (fault location defect\$3 signal\$1) AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
L14	26	(ishida.in. yamaguchi.in. hashimoto.in.) AND fault AND defect\$3 AND analysis AND ("IC" integrated circuit) AND (semi\$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:48

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L15	66	(stor\$3 memory medium media) AND current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:59
S1	109	defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:48
S2	63	analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:49
S3	0	transient power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S4	51	power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 17:00
S5	40	fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S6	40	current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50

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S7	37	potential AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S8	9	voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S9	9	current AND voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S10	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/22 09:34